

Search Notes



Application/Control No.

10/687,424

Examiner

Kin-Chan Chen

Applicant(s)/Patent under Reexamination

LIAW, JHON JHY

Art Unit

1765

SEARCHED

Class	Subclass	Date	Examiner
438	700	5/12/2005	K-cc
	702		
	703		
	706		
	710		
	714		
	719		
438	724	5/12/05	K-cc

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
EAST key words search, USPAT, US-PGPUB, EPO, JPO, Derwent, IBM-TDB, inventor search.	5/12/2005	K-cc